

<b>Search Notes</b> 	<b>Application/Control No.</b> 09/937,664	<b>Applicant(s)/Patent under Reexamination</b> OSAWA, HIDEHARU
<b>Examiner</b> Anabel M. Ton	<b>Art Unit</b> 2875	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner